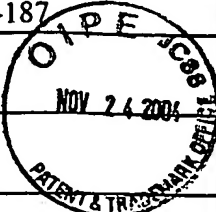


APPLICANT'S ART CITATION (Use several sheets if necessary)		Application		OFGS File No. P/1878-187			
		Applicant Sei HIRADE					
		Filing Date		Group Art Unit			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
/EB/	11-191896	07-1999	Japan			Abstract	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
Examiner /Emmanuel Bayard/ (04/10/2007)		Date Considered					
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APPLICANT'S ART CITATION (Use several sheets if necessary)		Application 10/773,670		OFGS File No. P/1878-187	
		Applicant Sei HIRADE			
		Filing Date February 6, 2004		Group Art Unit 2661	



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Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
/EB/	US-2002/0140603 A1	10-2002	Jeschke			
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	US-					

FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
/EB/		Search Report from European Patent Office issued September 20, 2004 in connection with
/EB/		corresponding application no. EP 04 25 0648

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